

Application/Control No.	Applicant(s)/Patent under Reexamination
10/091,047	SHIEH, HUGH H.
Examiner	Art Unit
Jason K. Gee	2134

SEARCHED					
Class	Subclass	Date	Examiner		
713	185	2/9/2006	JKG		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST - US_PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2/8/2006	JKG		
Google Scholar - Inventor Name Search	2/6/2006	JKG		
Palm - Inventor Name Search	2/6/2006	JKG		
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